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Exhibitor Introduction	SEMILAB is one of the key suppliers of metrology and inspection equipment for the display industry, based in Budapest, Hungary. We have R&D and product centers around the world, including the USA, Germany and China, and direct sales and service offices in all the major markets, including the USA, Japan, Korea, China, Taiwan and Singapore.  Our customer-centric global support enables close collaboration with industry partners to understand and fulfill the requirements of the latest manufacturing and quality control processes of the microelectronics industry in order to serve customer satisfaction and enabling a smarter future	
Exhibit Description	SEMILAB provides state-of-the-art metrology solutions for semiconductor device manufacturers, both in-line and R&D segments, and is a strategic metrology supplier of leading wafer manufacturers, IC device makers in the More-than-Moore market segment, solar and display industries worldwide.  We cover the entire R&D lifecycle of product innovation, ranging from innovative research, measurement development, product design and	



	manufacturing to implementation, integration, and maintenance. With our	
	47 product lines and over 300 unique products, our growing portfolio	
	offers a variety of metrology solutions based on optical and electrical	
	measurement technologies, thin film applications, and automation	
	developments based on customer requirements, from manual operation	
	to complete and factory scale automation.	
	Spectroscopic Ellipsometry (SE),	
	Infrared Spectroscopic Ellipsometry (FPT-EIR)	
	Spectroscopic Reflectometry (SR)	
<b>Exhibit Product</b>	Imaging Spectroscopic Reflectometry (ISR)	
	Microwave Photoconductive Response(u-PCR)	
	Line mura inspection	
	Four-point Probe	